

Notice of References Cited	Application/Control No. 10/812,076	Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner Cheukfan Lee	Art Unit 2625	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,229,627	05-2001	Taguchi et al.	358/461
*	B	US-6,747,765	06-2004	Kitamura et al.	358/497
	C	US-			
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	I	US-			
	J	US-			
	K	US-			
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	M	US-			

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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